rf/microwave instrumentation



M1, M2 Antenna

Model ATL80M1G,

80MHz-1000MHz

The Model ATL80M1G is a wide band, high-gain, log periodic antenna that provides field intensities of up to 500 V/M. With an average gain of 7.5 dB over isotropic and gain flatness of ± 1 dB, the Model ATL80M1G supplies the constant, high-intensity fields necessary for RFI/EMI field testing within and beyond the confines of a shielded room. It can also be used as a receiving antenna for RF emissions testing. The Model ATL80M1G is compact and lightweight for ready mobility, yet is built tough for the extra demands of outdoor use and easily mounts on a flat surface or tripod. Similar to our popular Model ATL150M1G the Model ATL80M1G provides the lower frequency response required for many often used test specifications. The Model ATL80M1G series allows polarization change without removing the antenna from the tripod.

	SPECIFICATIONS
FREQUENCY RANGE	80–1000 MHz
POWER INPUT (maximum)	See Graph
POWER GAIN (over isotropic)	6.5 dBi minimum 7.5 dBi average
GAIN FLATNESS	± 1.0 dB
IMPEDANCE	50 ohms nominal
VSWR Maximum Average	
BEAM WIDTH (average) E Plane H Plane	
FRONT TO BACK RATIO (minimum)	15 dB
CONNECTOR	See Model Configurations
MOUNTING PROVISIONS	Wall bracket included. May also be tripod mounted using the optional TP1000B. Also includes non- metallic mast, 20 inches long, for vertical mounting.
WEIGHT	7.7 kg (17 lb)
SIZE (WxHxD) Assembled	

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Rotation Mechanism

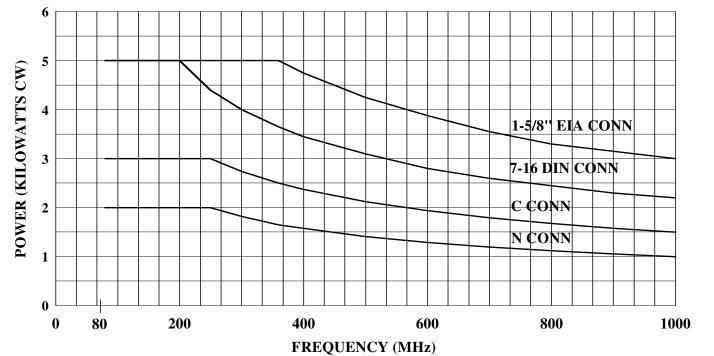
SPECIFICATIONS

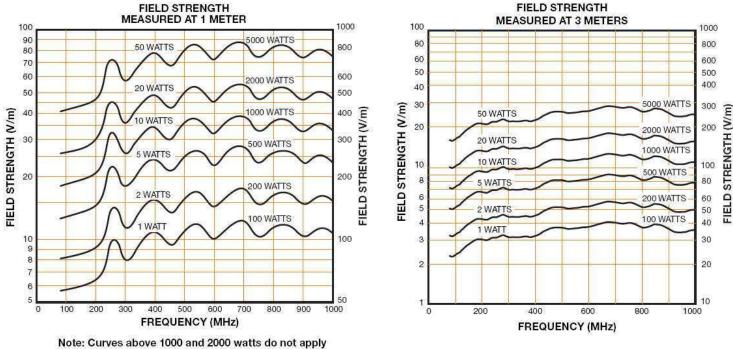
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MODEL CONFIGURATIONS		
Model	Connector	Power Input
ATL80M1G	N (f); C (f) for high power	See graph
ATL80M1GM1	7-16 DIN	See graph
ATL80M1GM2	1-5/8″ EIA	See graph







past power-frequency limits of the antenna.

Field space has been measured in free-space conditions. Individual shielded rooms, amplifiers, and test system conditions will influence performance. Field strength also varies with frequency and position of antenna and EUT in non-anechoic testing environments.

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